TOSHIBA Transistor Silicon PNP Epitaxial Type (PCT process)

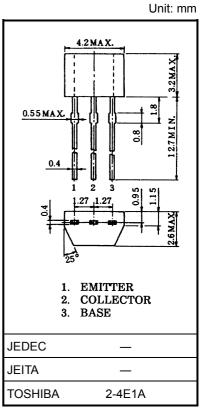
## 2SA1297

# Power Amplifier Applications Power Switching Applications

- Low saturation voltage:  $V_{CE (sat)} = -0.5 \text{ V (max)} @I_{C} = -2 \text{ A}$
- Complementary to 2SC3267.

#### Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Collector-base voltage	$V_{CBO}$	-20	V
Collector-emitter voltage	V <sub>CEO</sub>	-20	V
Emitter-base voltage	V <sub>EBO</sub>	6	V
Collector current	I <sub>C</sub>	-2	Α
Base current	Ι <sub>Β</sub>	-0.5	Α
Collector power dissipation	PC	400	mW
Junction temperature	Tj	150	°C
Storage temperature range	T <sub>stg</sub>	-55~150	°C



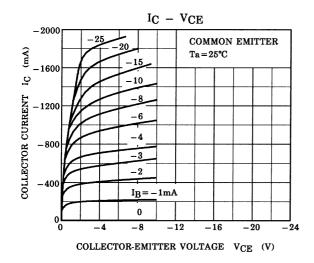
Weight: 0.13 g (typ.)

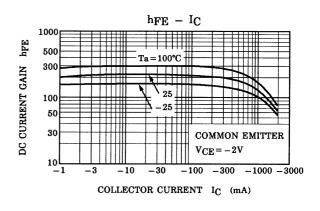
### **Electrical Characteristics (Ta = 25°C)**

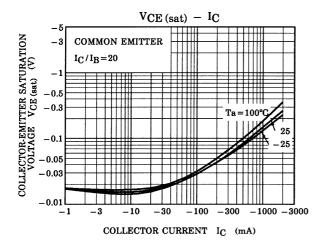
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	$V_{CB} = -20 \text{ V}, I_E = 0$	_	_	-0.1	μΑ
Emitter cut-off current	I <sub>EBO</sub>	$V_{EB} = -6 \text{ V}, I_{C} = 0$	_	_	-0.1	μА
Collector-emitter breakdown voltage	V (BR) CEO	$I_C = -10 \text{ mA}, I_B = 0$	-20	_	_	V
Emitter-base breakdown voltage	V <sub>(BR) EBO</sub>	$I_E = -0.1 \text{ mA}, I_C = 0$	-6	_	_	V
DC current gain	h <sub>FE (1)</sub> (Note)	$V_{CE} = -2 \text{ V}, I_{C} = -0.1 \text{ A}$	120	_	400	
	h <sub>FE (2)</sub>	$V_{CE} = -2 \text{ V}, I_{C} = -2 \text{ A}$	40	_	_	
Collector-emitter saturation voltage	V <sub>CE</sub> (sat)	$I_C = -2 \text{ A}, I_B = -0.1 \text{ A}$	_	_	-0.5	V
Base-emitter voltage	V <sub>BE</sub>	$V_{CE} = -2 \text{ V}, I_{C} = -0.1 \text{ A}$	_	_	-0.85	V
Transition frequency	f <sub>T</sub>	$V_{CE} = -2 \text{ V}, I_{C} = -0.5 \text{ A}$	_	120	_	MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$	_	40	_	pF

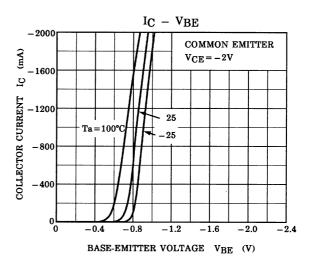
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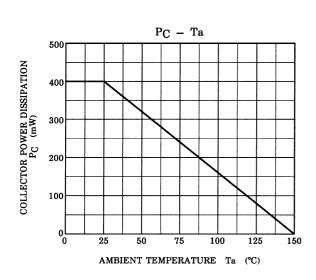
Note: hFE (1) Y: 120~240, GR: 200~400

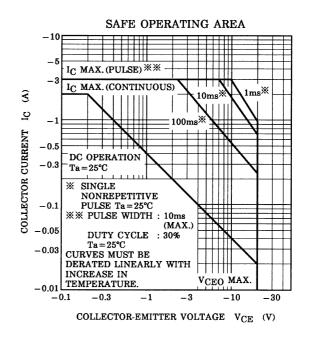












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